

RD39 Status Report 2011-2012

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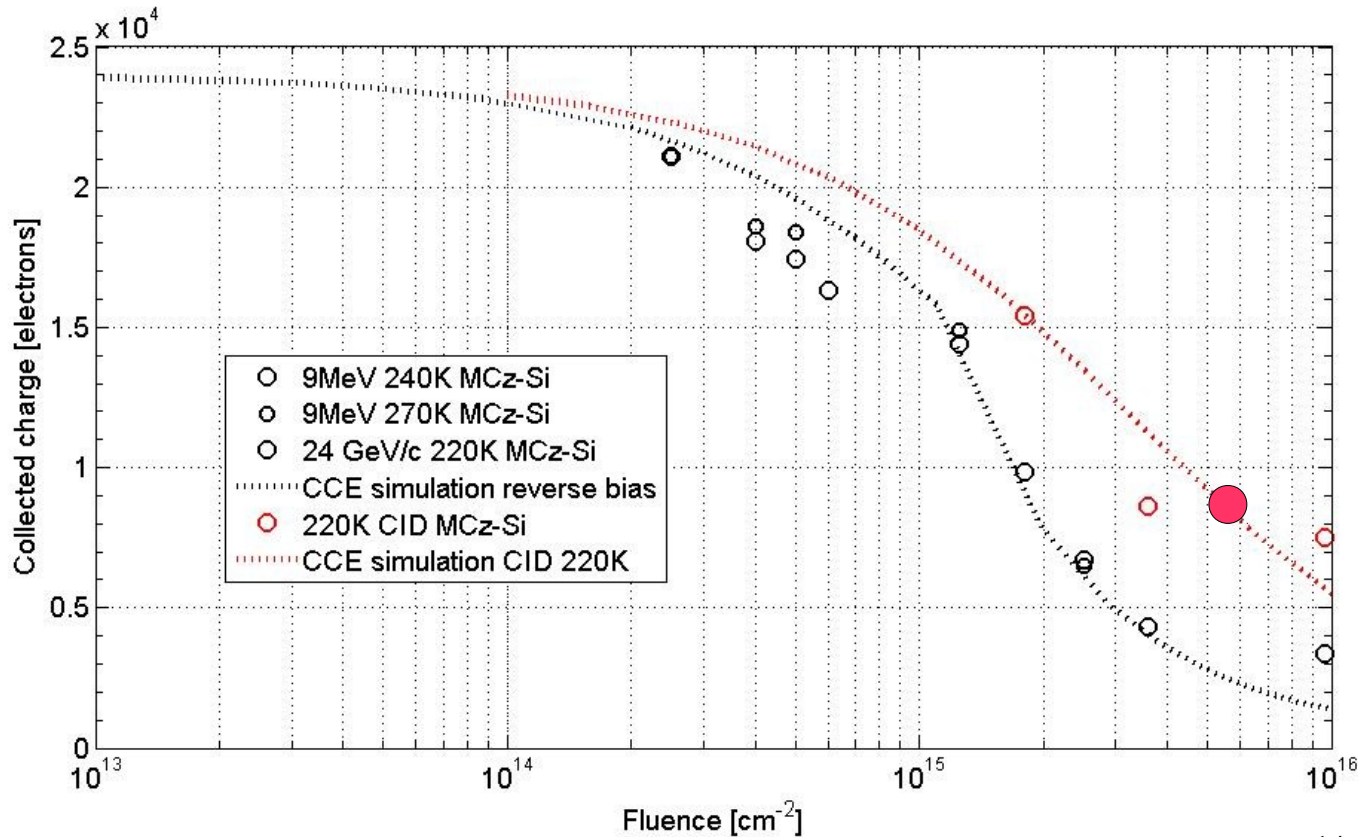
<http://rd39.web.cern.ch/RD39/>

Outline

- Review Charge Injected Detector (CID) development
- Cryogenic Beam Loss Monitoring (BLM) for LHC
- BLM experimental results
 - Test beams
 - Transient Current Technique (TCT) measurements with laser
- Near term plans of BLM project
- Summary

Expected CCE of CID at -50°C

Strips Pixels & Cryogenic Beam Loss Monitor



- Simulation takes into account linear trapping
- $\beta=0.01 \text{ cm}^{-1}$
- \sqrt{x} E-field distribution is assumed

$$W_{pin} \propto \left(1 - \frac{x}{d}\right)$$

$$W_{CID} \propto \sqrt{x}$$

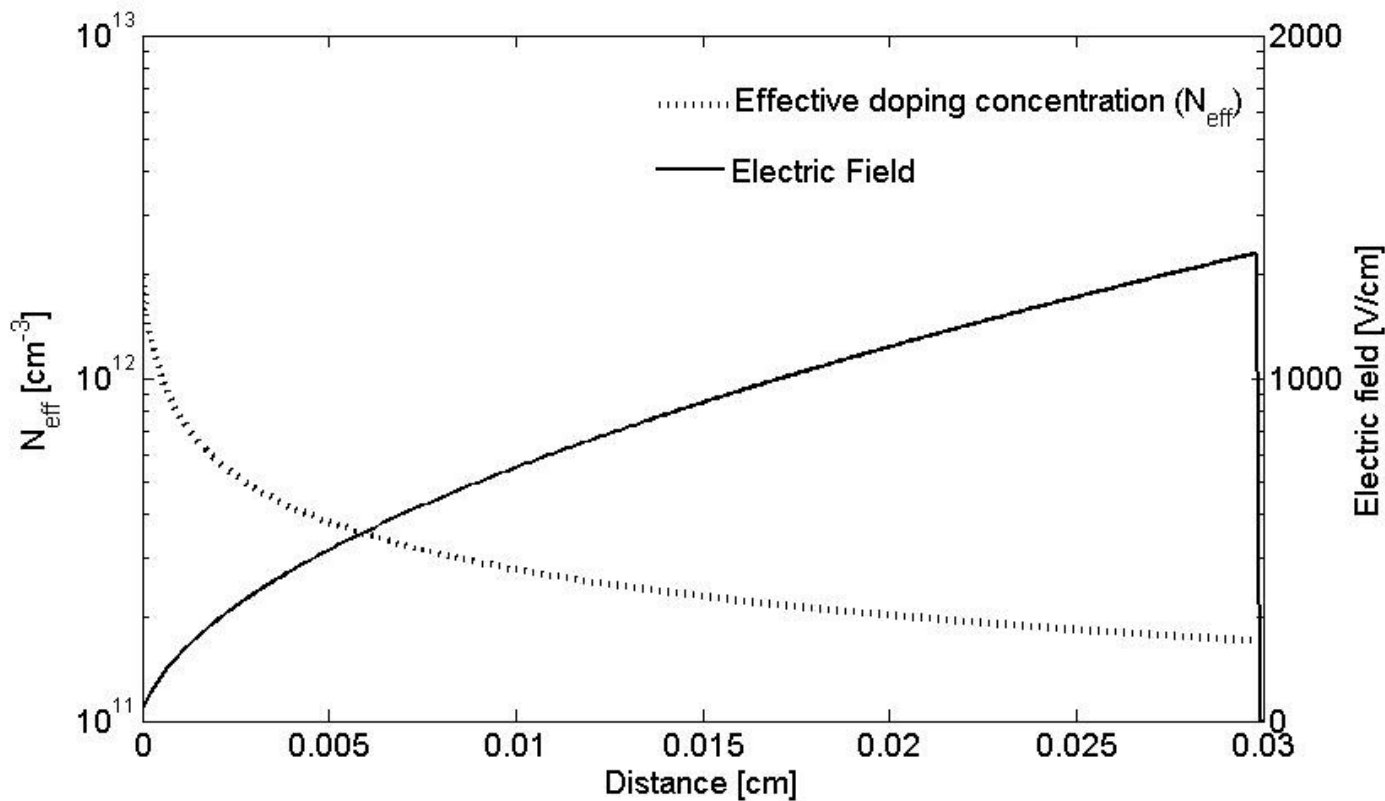
$$CCE = CCE_{Geometrical} \times CCE_{trapping} = \frac{W}{d} \times e^{-t_{dr} / \tau_{trapping}}$$

$1 \times 10^{14} \text{ n}_{eq}/\text{cm}^2$	$\tau_{trap} = 10\text{ns}$
$1 \times 10^{15} \text{ n}_{eq}/\text{cm}^2$	$\tau_{trap} = 1\text{ns}$
$1 \times 10^{16} \text{ n}_{eq}/\text{cm}^2$	$\tau_{trap} = 0.1\text{ns}$

Charge Injected Detector (CID) –Operational Principle

The electric field is controlled by charge injection, i.e. charge is trapped but not detrapped at “low” temperature

$$\tau_{trapping} = \frac{1}{\sigma_{e,h} v_{th} N_t} \quad \tau_{detrapping} = \frac{1}{\sigma_{e,h} v_{th} e^{\frac{-E_t}{kT}}}$$

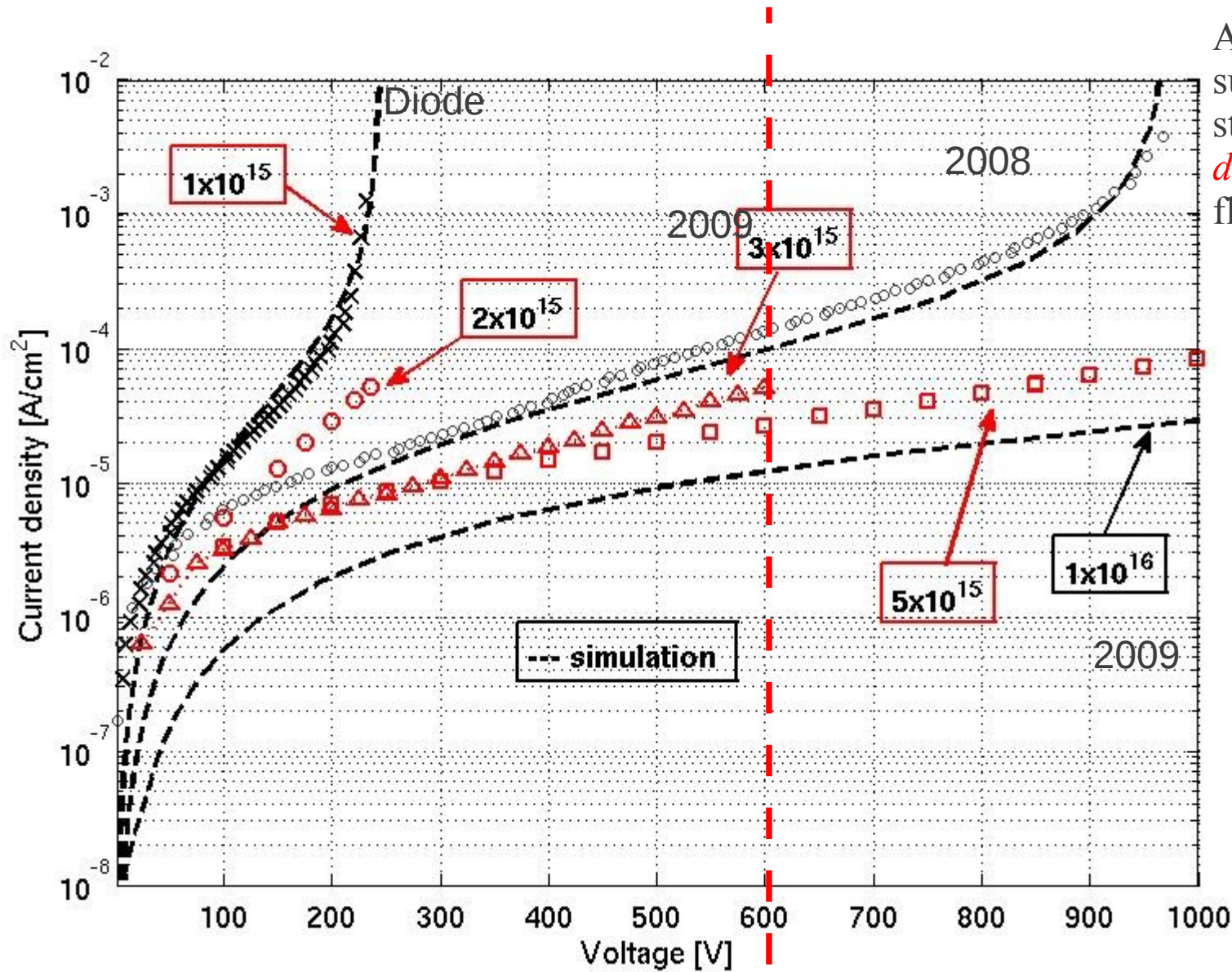


Electric field is extended through entire bulk regardless of irradiation fluence.

Electric field is proportional to square of distance $E(x) \sim \sqrt{x}$

Detector is “fully depleted” at any bias or irradiation fluence

Forward IV characteristics of CID

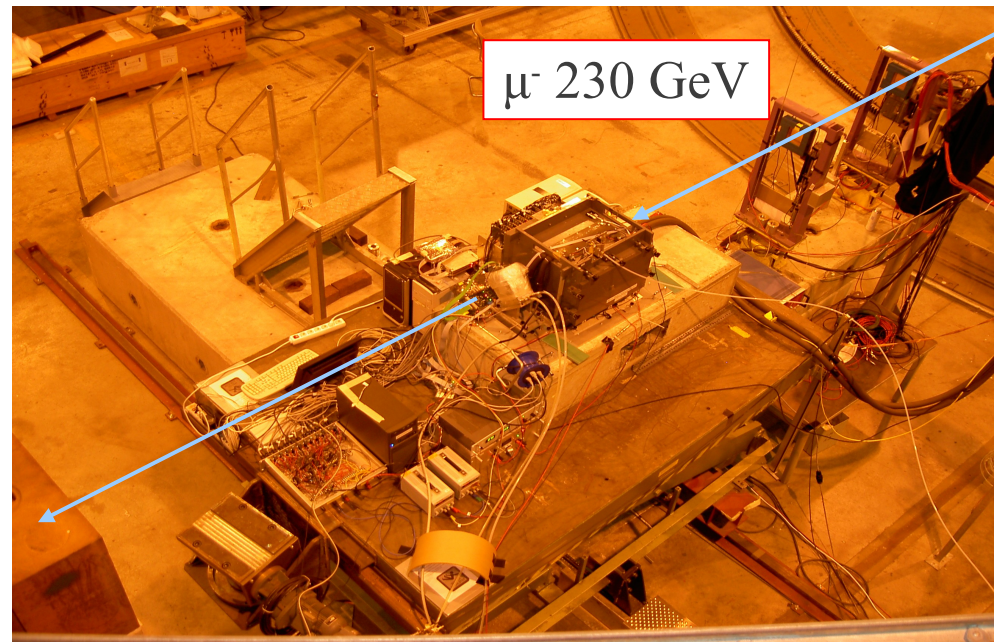
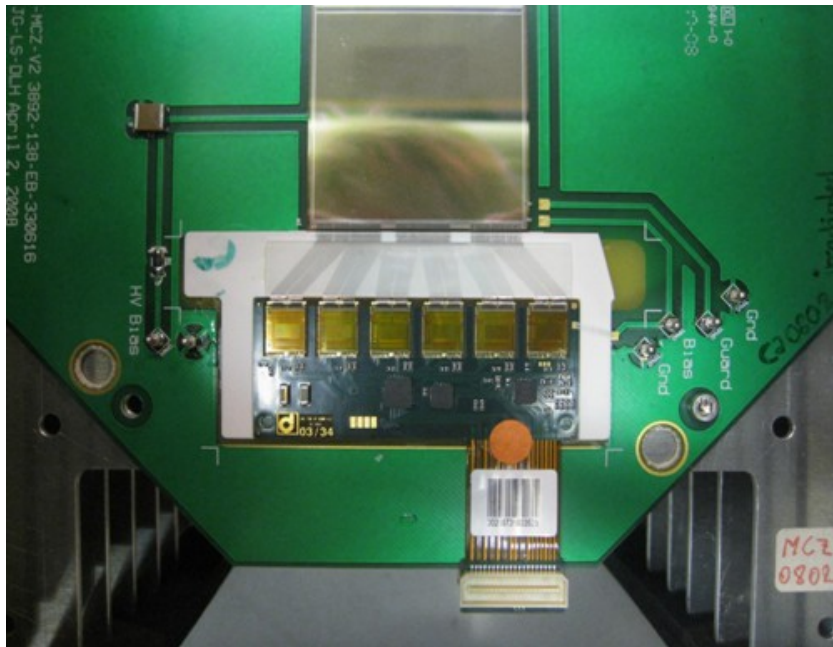


At given voltage, ensuring sufficient electric field $E(x)$ strength, forward current *decreases* when irradiation fluence increases

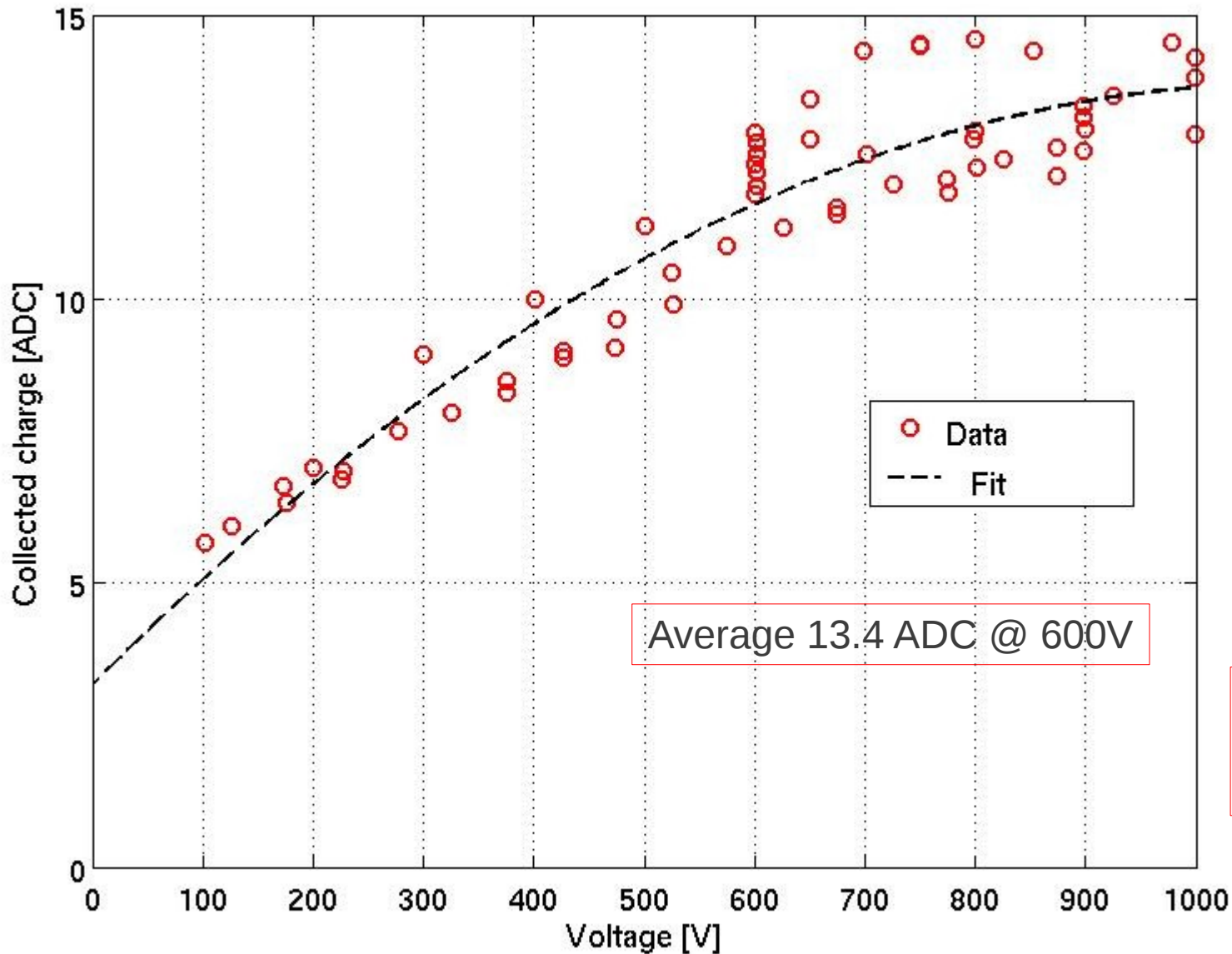
IV data recorded at -50°C

Test Beam experiment on CID detectors

- Sensors investigated
 - $2 \times 10^{15} \text{ n}_{\text{eq}}/\text{cm}^2 \text{ n}^+/\text{p}/\text{p}^+ \text{ MCz-Si}$
 - $5 \times 10^{15} \text{ n}_{\text{eq}}/\text{cm}^2 \text{ p}^+/\text{n}/\text{n}^+ \text{ MCz-Si}$ (in 2008 $3 \times 10^{15} \text{ n}_{\text{eq}}/\text{cm}^2 \text{ p}^+/\text{n}/\text{n}^+ \text{ MCz-Si}$)



$5 \times 10^{15} n_{e q} / \text{cm}^2$ results - Collected charge vs V



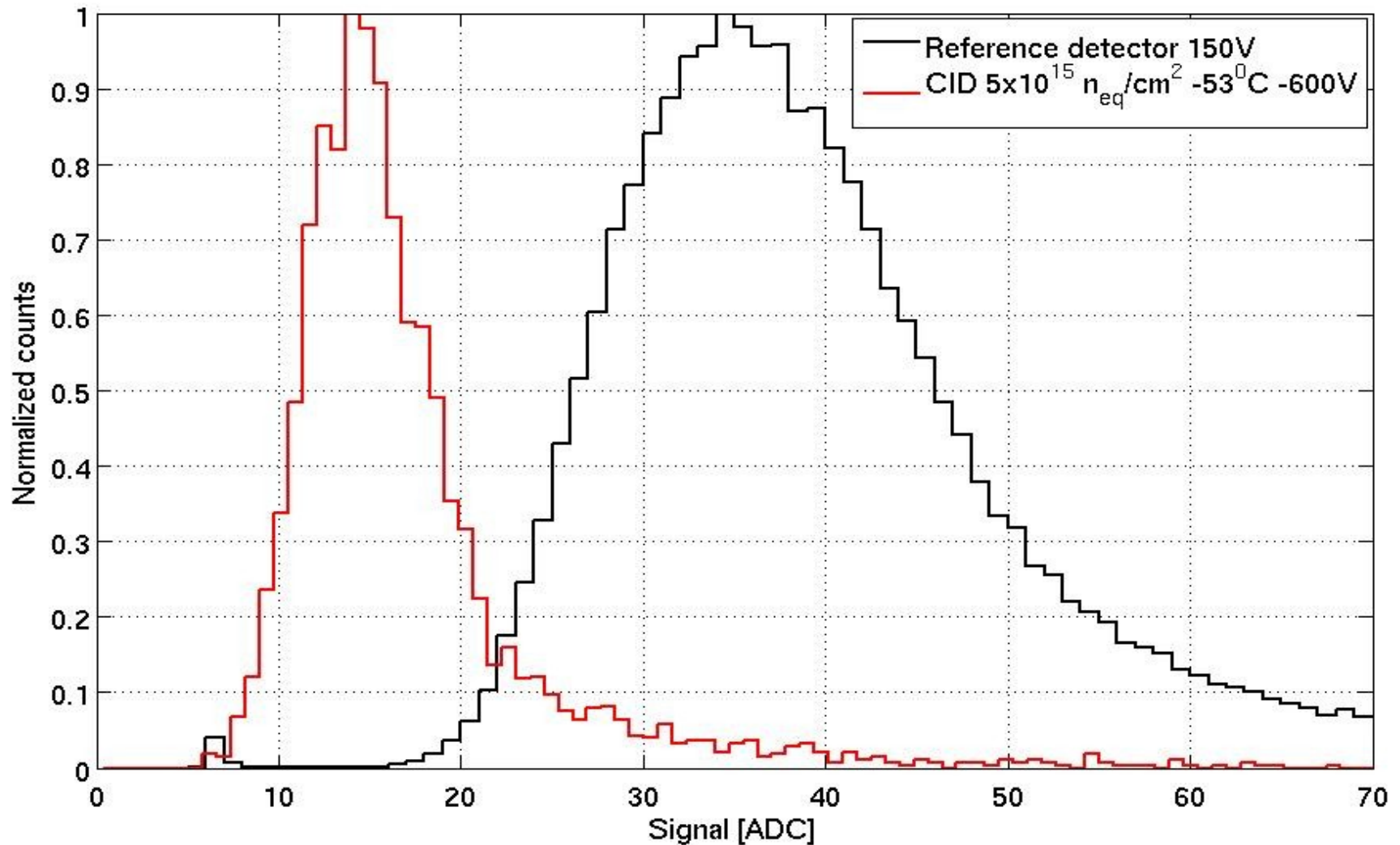
1 ADC $\approx 600e^-$

Full charge measured by 12 reference planes is 40 ADC

One data point ○ is MPV of typically $>20\,000$ events seen by telescope

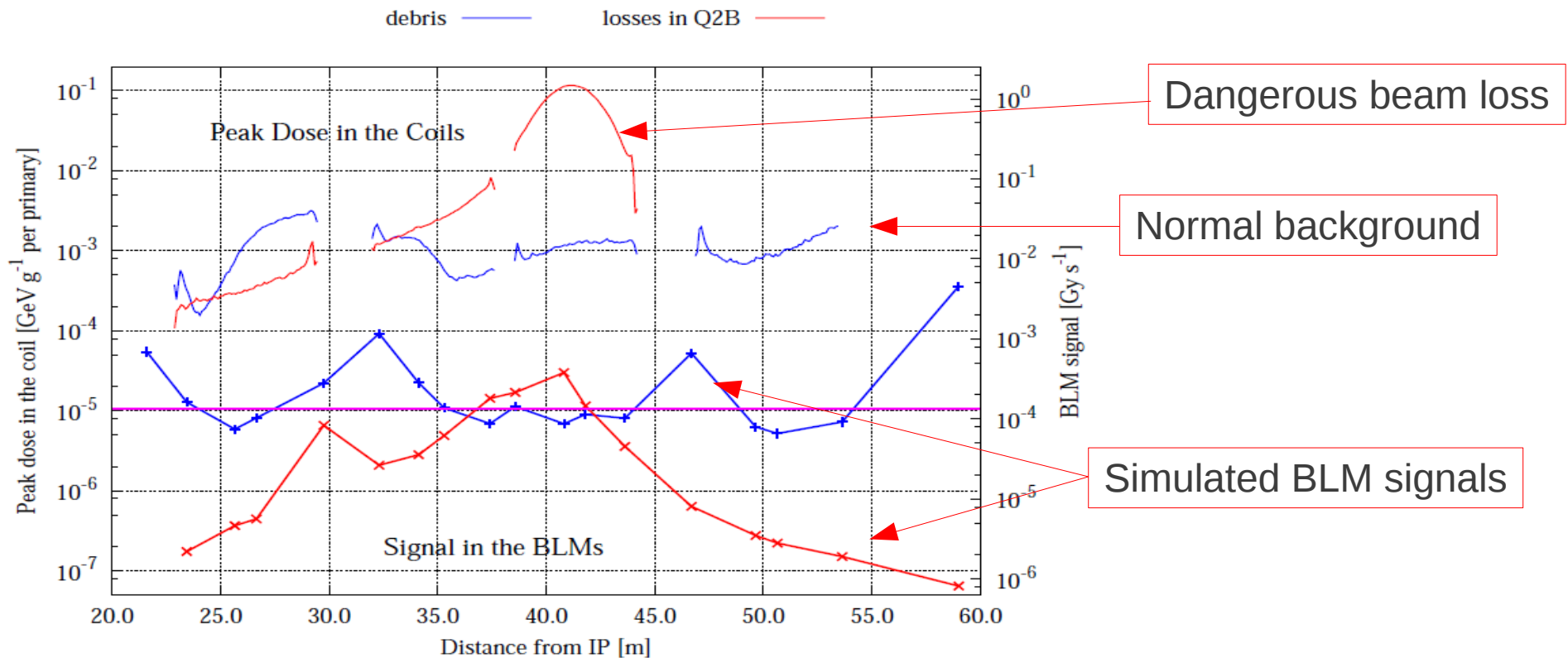
Relative Charge Collection Efficiency is about 33% while the noise $\approx 1000e^-$

$5 \times 10^{15} n_{eq}/cm^2$ results - Collected charge vs non-irrad



Beam Loss Monitoring (BLM) for LHC

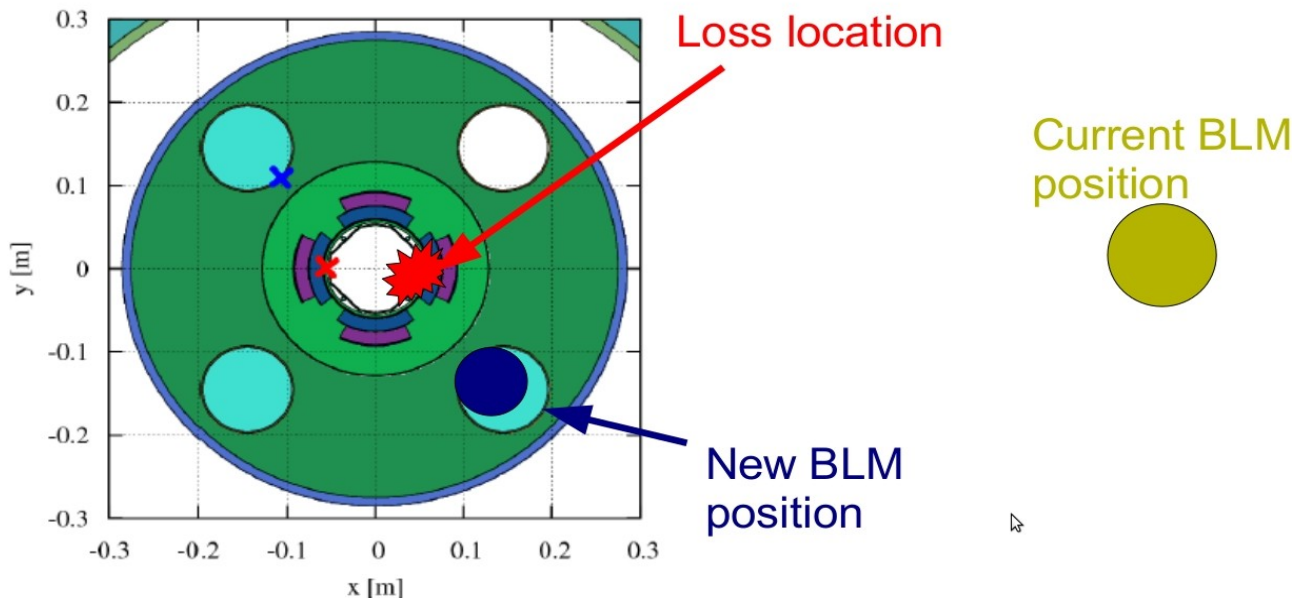
- There are currently about 4000 BLMs in LHC
- BLM is needed in order to give warning signal of a beam loss that might result in magnet quenching.
- In current BLM devices, it is possible that signal of a dangerous beam loss is hidden behind of background induced by normal beam debris.



Proposed solution

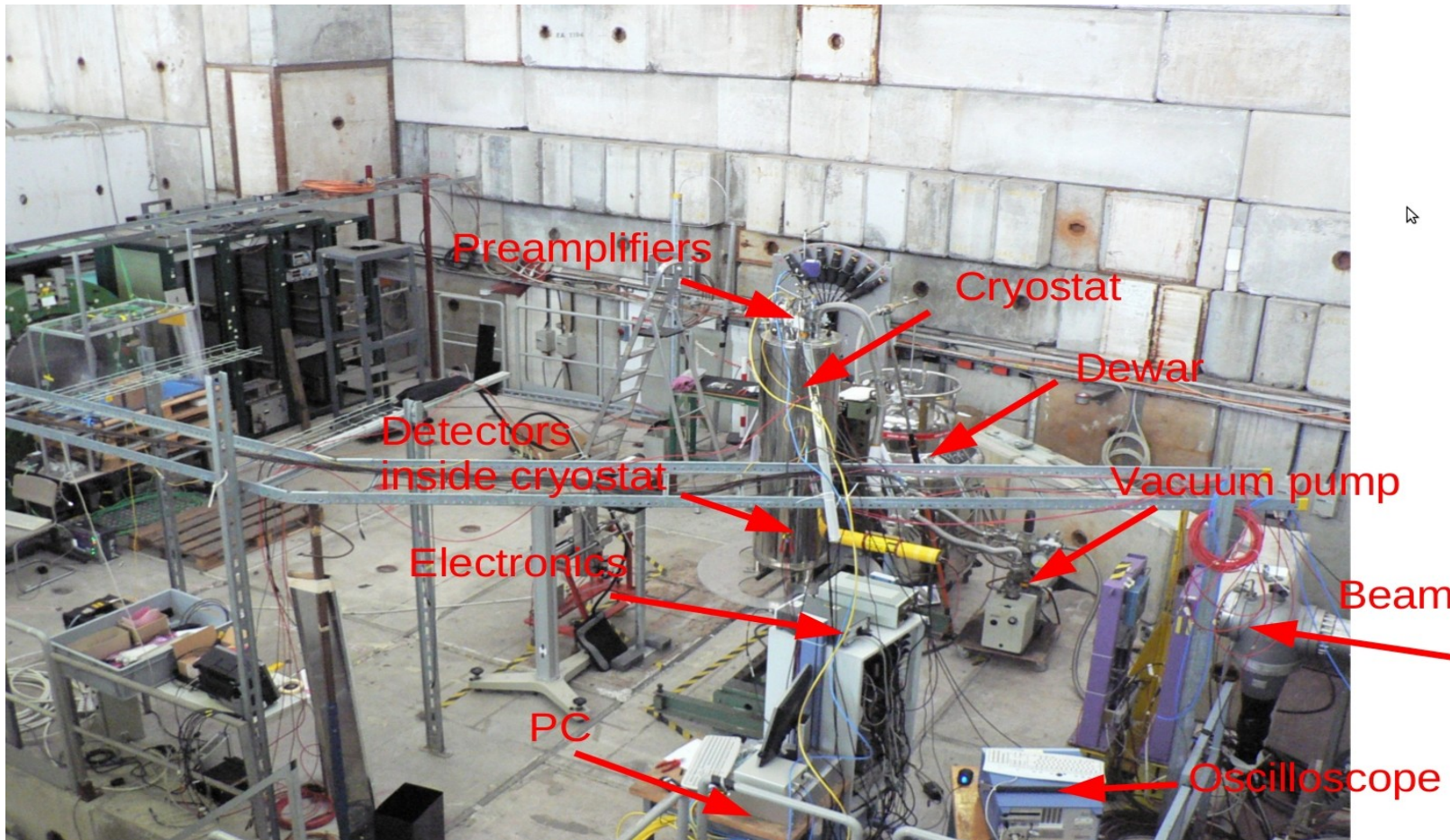
- Place the BLM inside of cold mass, close to interaction point
- CERN workgroup: B. Dehning, M. Sapinski, T. Eisel, C. Kurfuerst
- Challenge: Si detector should operate at LHe temperature $<2\text{K}$ and should simultaneously be radiation hard up to 1 MGy.
- At LHe temperature there is no annealing of radiation defects + shallow donor/acceptor impurities are not ionized
- For more information about BLM project see “Cryogenic Beam Loss Monitors workshop”

<http://indico.cern.ch/conferenceDisplay.py?confId=156472>



Experimental work this far

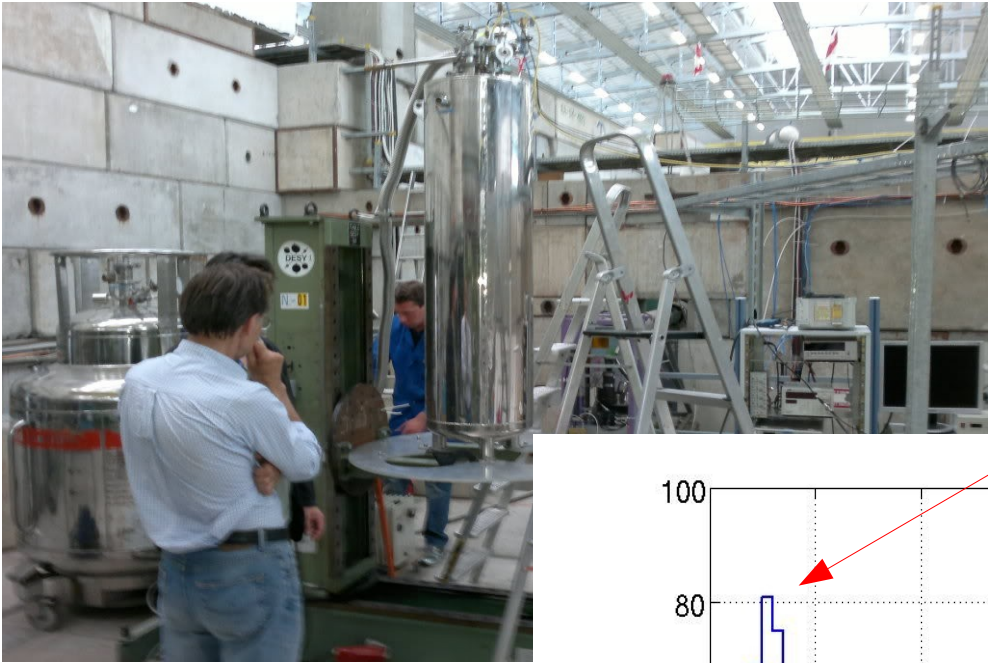
- Test beam measurements at CERN, 9 GeV particles from PS
- Transient Current Technique (TCT) measurements at CERN Cryolab



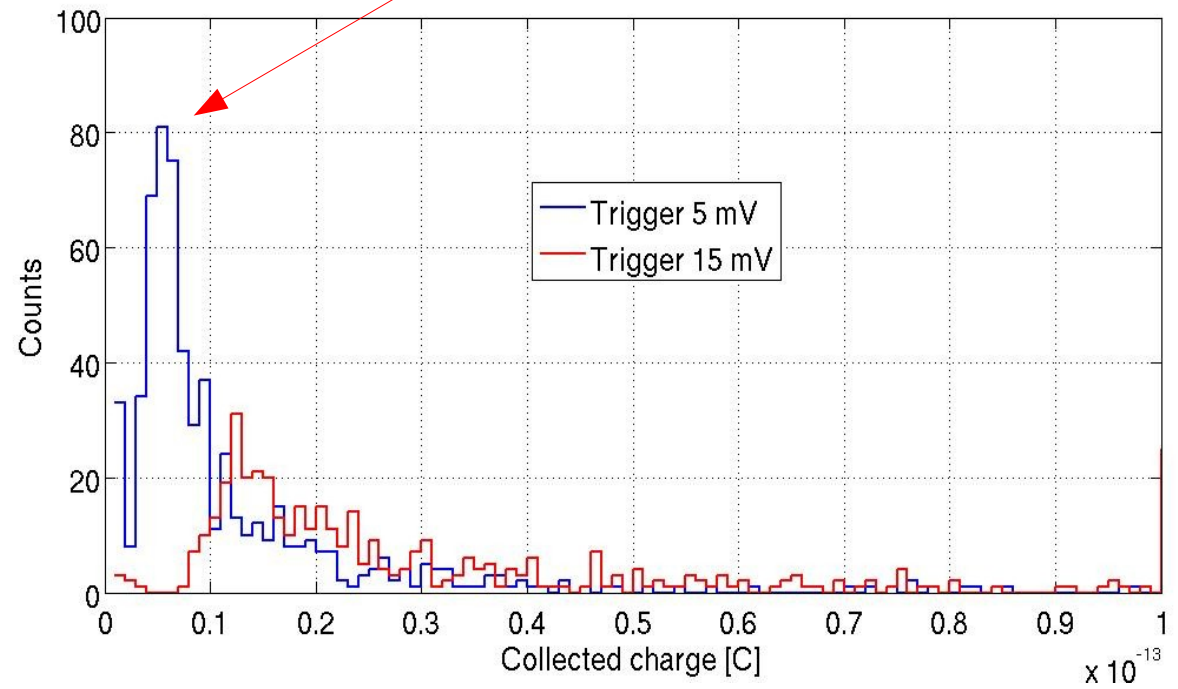
12.06.12

J.Härkönen, 110th LHCC Open Session, 13.06.2012, CERN

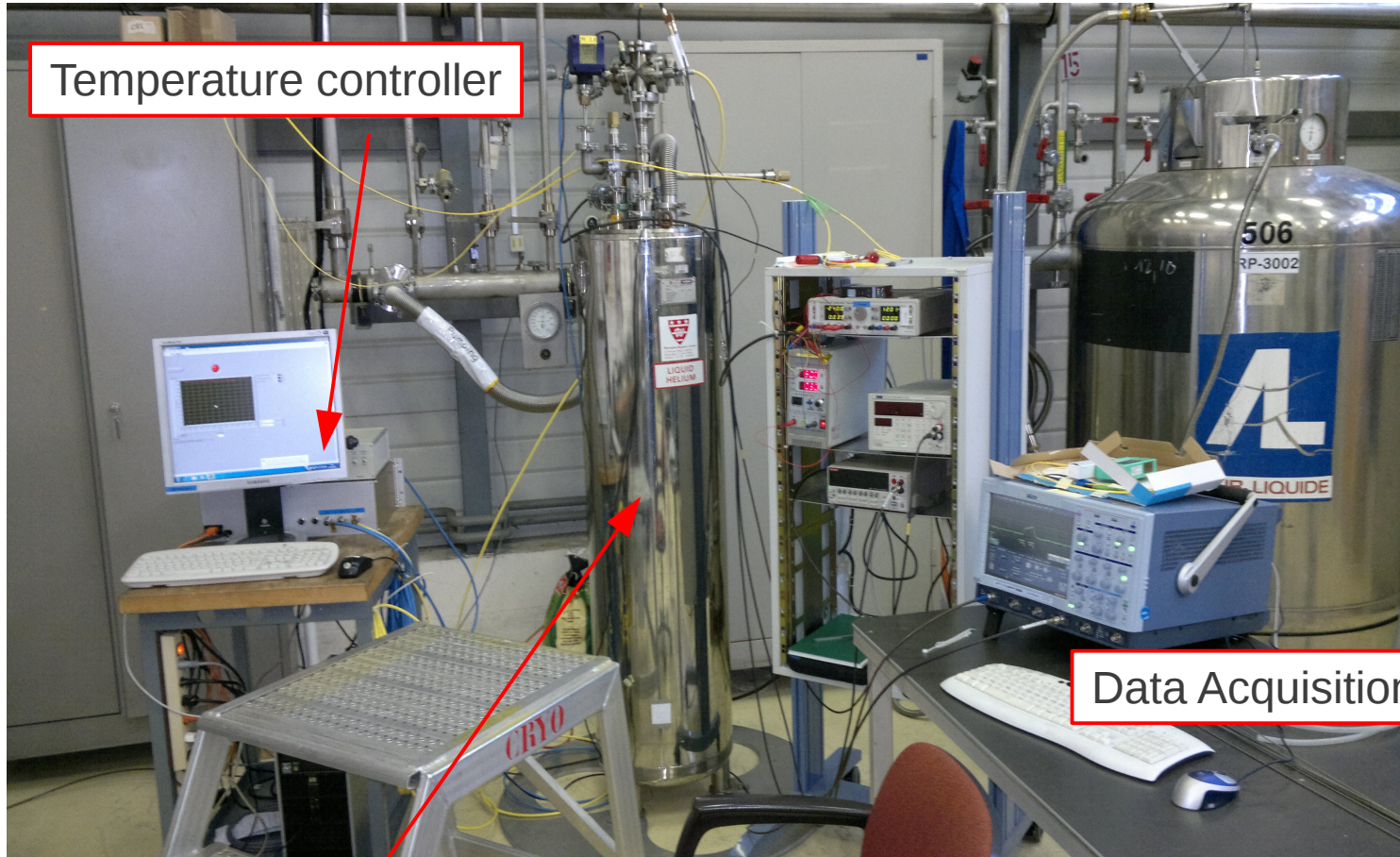
Test Beam at CERN PS



MPV $\approx 4\text{fC}$ i.e. 1 MIP charge



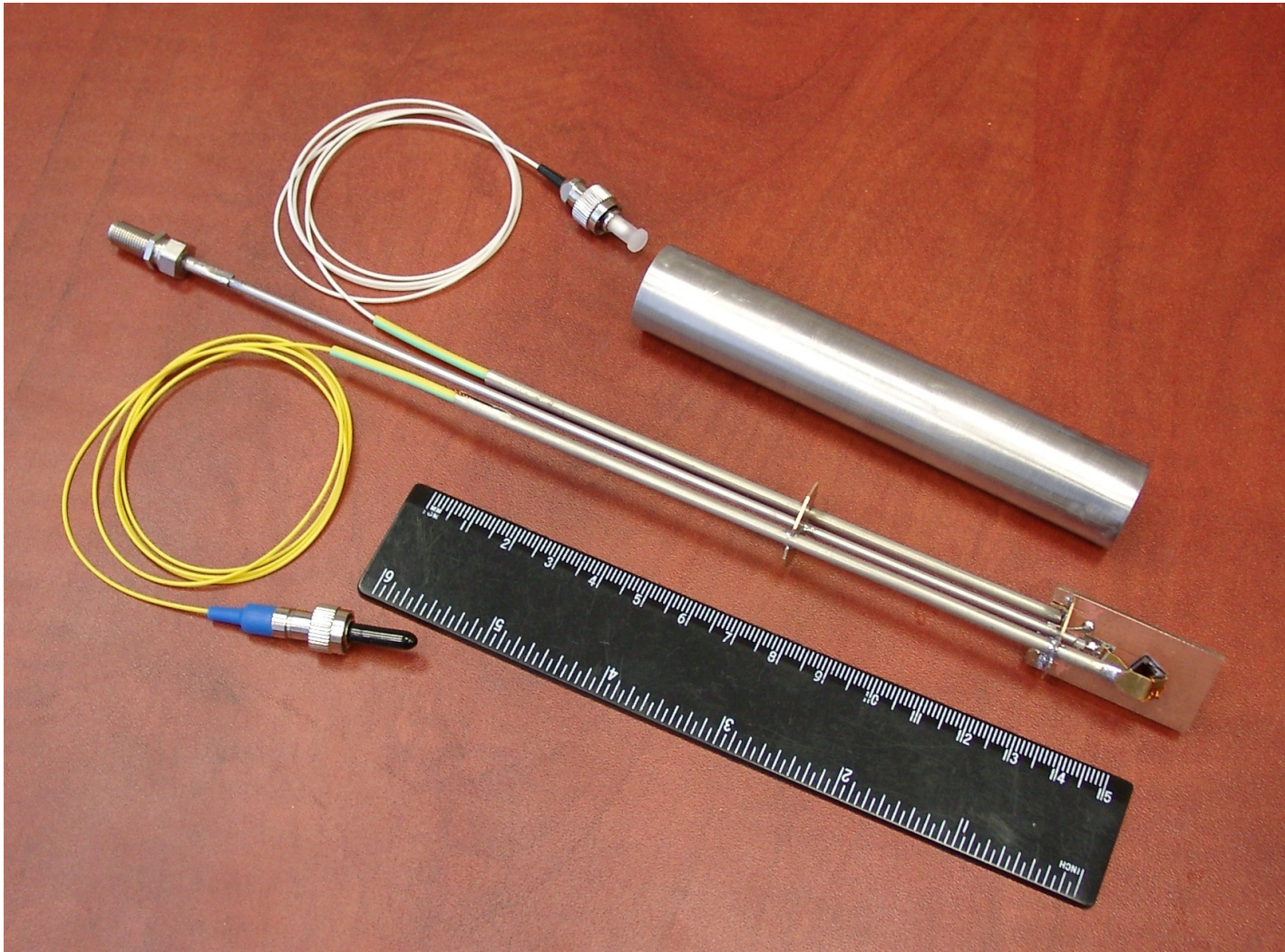
TCT setup @ Cryolab



- RD39 Cryo-TCT
- LHe cryosystem made by Thomas Eisel

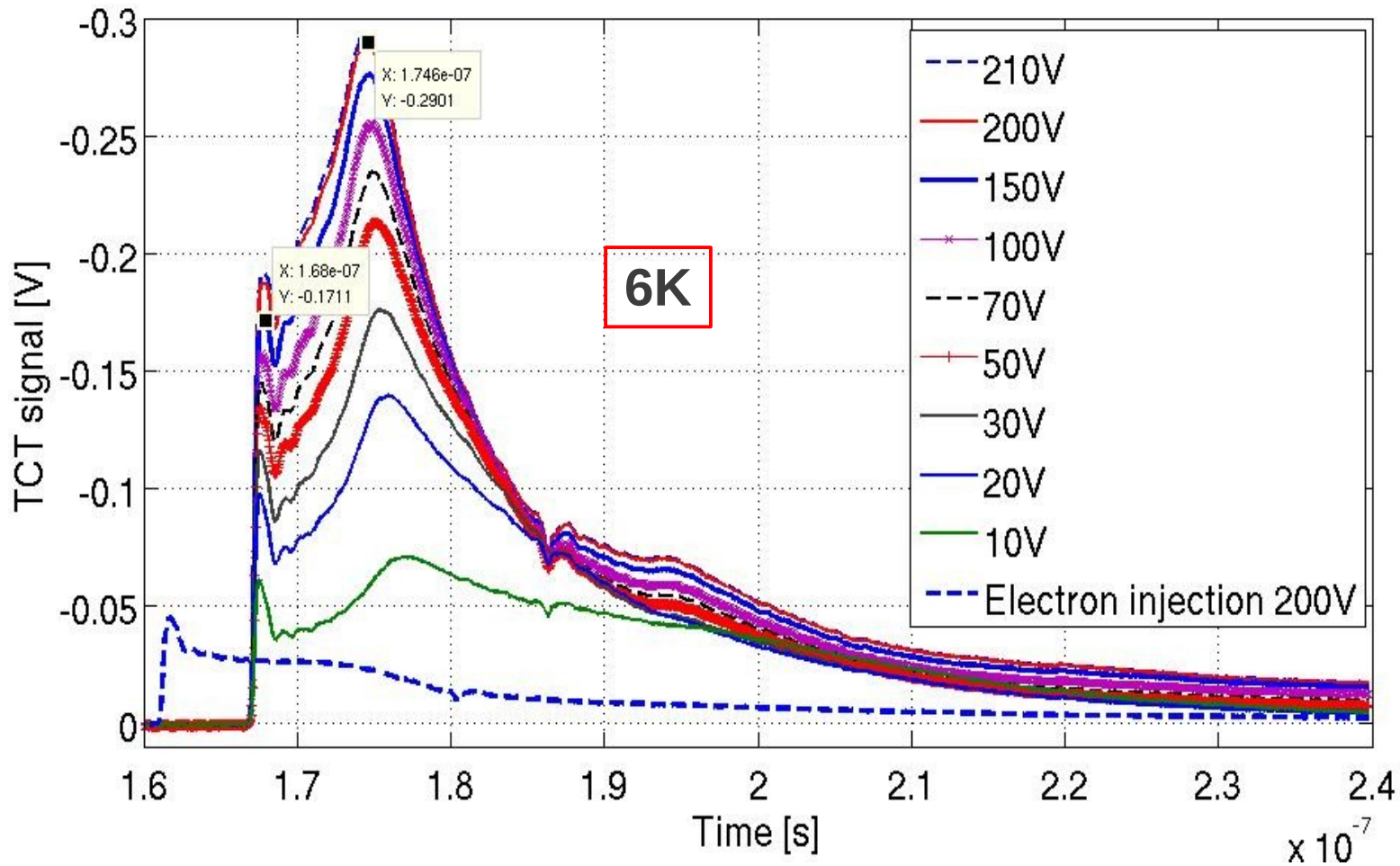
Cryogenic system is presented at:
Cryogenic Beam Loss Monitors workshop
Cryogenics for East Hall experiments 5'
Speaker: Thomas Eisel (Technische Universitaet Dresden)

Detector arrangement



- Detector delivered by PTI
- Degenerately doped $p^+/n^-/n^+$ sensor
- Thickness $300\mu\text{m}$
- Optical illumination both sides
- Sample holder etc designed by Vladimir Eremin

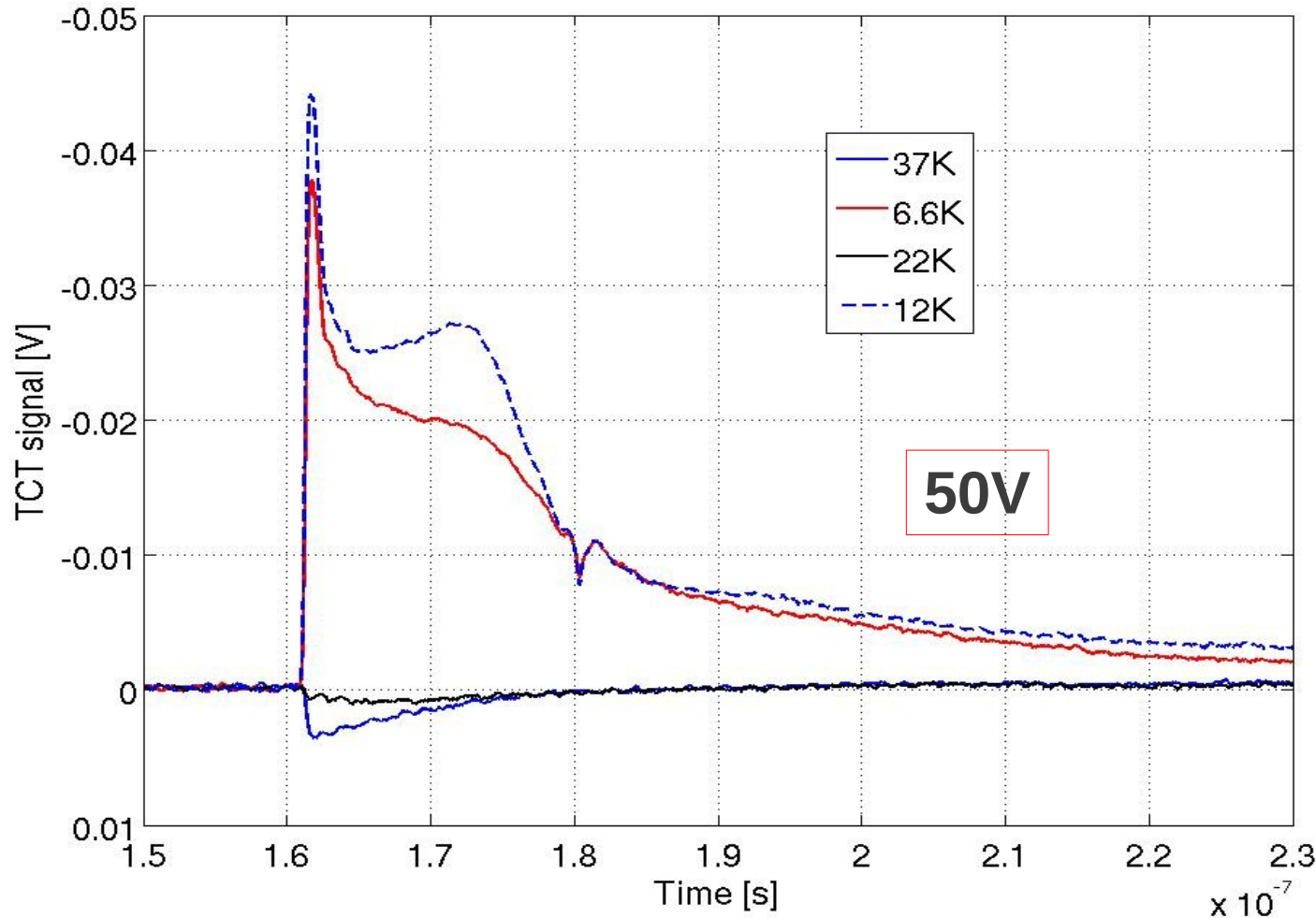
TCT measurement in CID mode



- Detector *non-irradiated*
- CID operation up to 200V
- Forward current $\sim 100\mu\text{A}$
- Drift time $\approx 6\text{-}7\text{ns}$ for holes
- Very long $\sim 50\text{ns}$ tail in signal

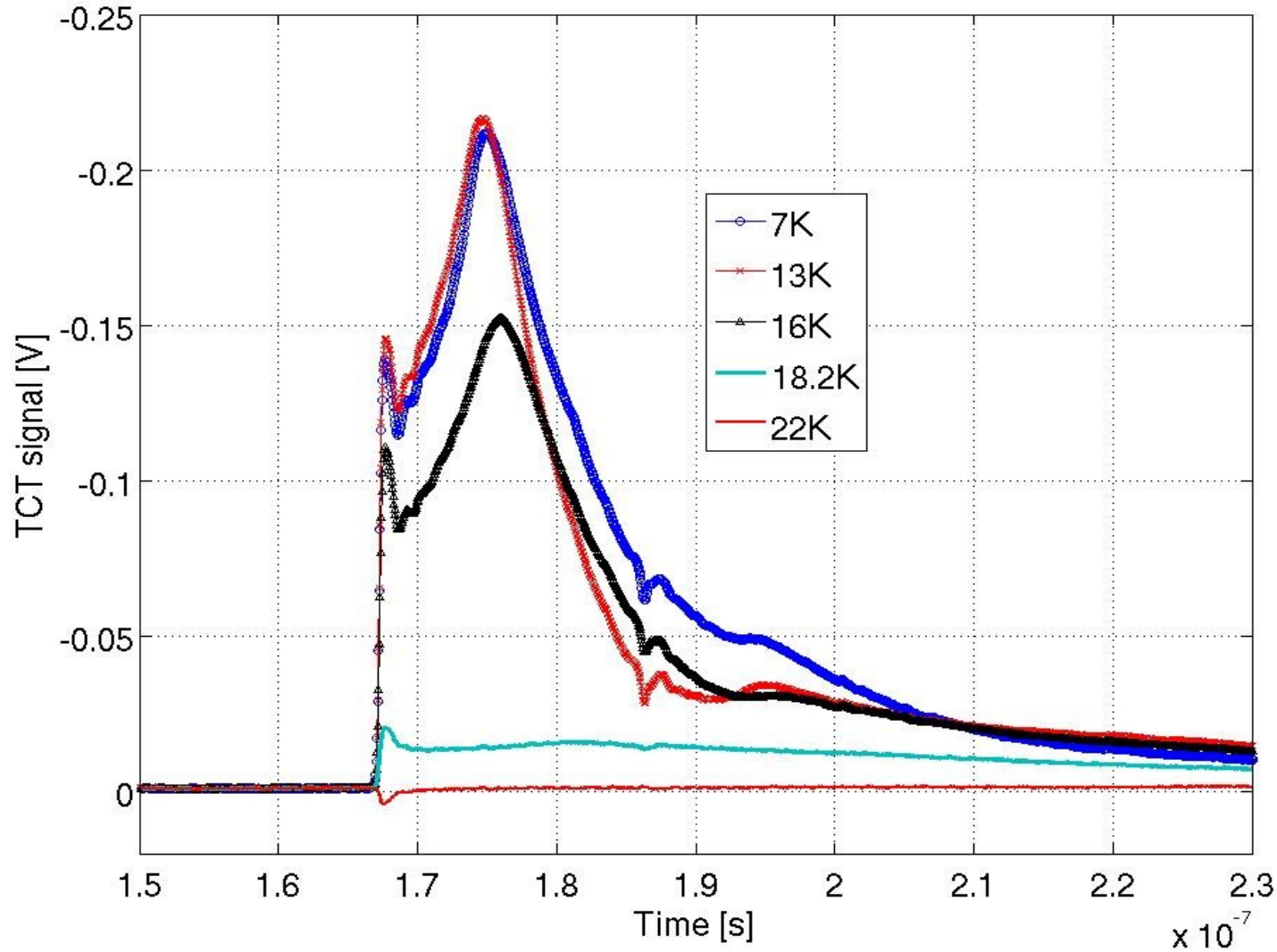
Back side illumination, i.e. hole current transient

CID Electron current transient vs Temperature



- In principle, CID concept should not work unless detector is heavily irradiated, i.e. lot of deep levels.
- Nice signal $T < 15K$
- $T > 15K$ signal polarity inverts and amplitude decreases

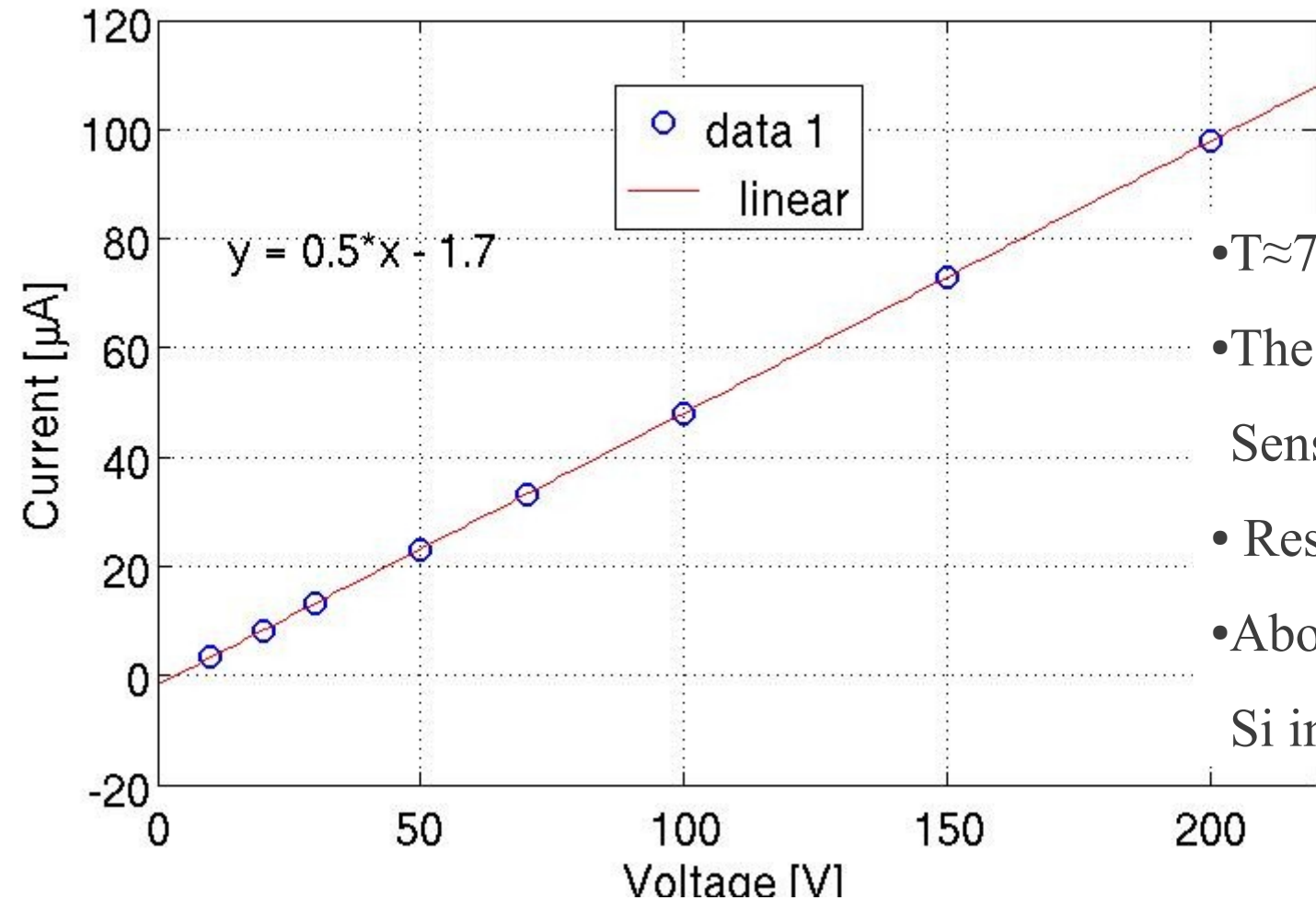
CID Hole current transient vs T



- Nice signal T < 15K
- T > 15K signal polarity inverts and amplitude decreases

50V

Ohmic behaviour with forward bias



• $T \approx 7\text{K}$

• The resistance is $2\text{M}\ \Omega$

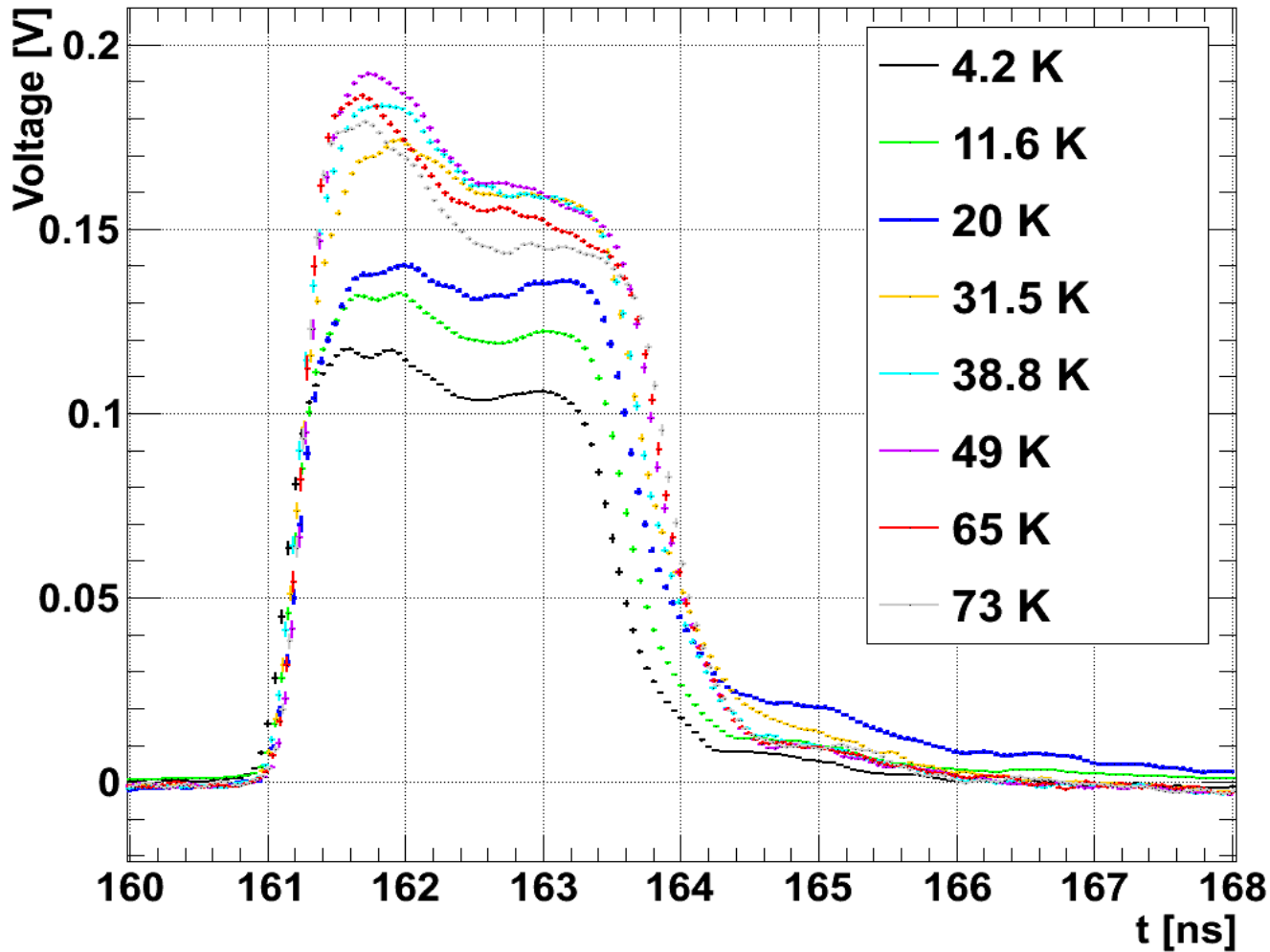
Sensor $0.5\text{cm} \times 0.5\text{cm} \times 0.03\text{cm}$

• Resistivity $\approx 17\text{M}\ \Omega\text{cm}$.

• About 50 times more than
Si intrinsic resistivity at RT

Reverse bias operation

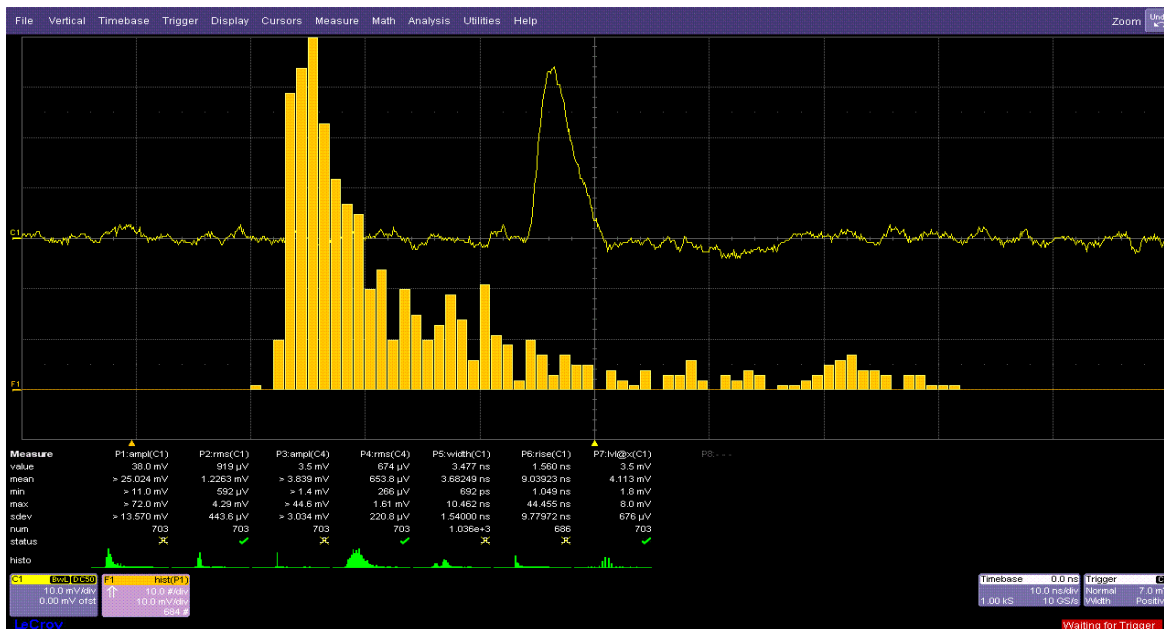
Si electron pulses at 3330 V/cm



Measurement by
C. Kurfürst

Near term plans

- August 2012 “warm” test in a beam
- November 2012 high intensity (irradiation) test beam with cryogenics at CERN PS T7 area.
- Production of BLM dedicated silicon detectors ongoing. Activity coordinated by Vladimir Eremin, Ioffe PTI



Summary

- Si detectors produced by RD39 are successfully tested in particle beams and by laser TCT setups
- Non-irradiated detector provides signal $T < 15\text{K}$, i.e. below shallow level freeze-out T in Si
- Polarization due to radiation defects at deep cryogenic temperature is likely to be a major challenge > CID operation might be mandatory.
- At very low temperatures and CID mode, symmetrical behaviour, i.e. electron and hole current transients apparent, both.
- IV is ohmic with forward bias
- Current is ≈ 0 reverse bias
- When dopant freeze-out, Si bulk turns into insulator.
- Forward current establishes $E(x)$ over $2\text{M}\Omega$ resistor
- Reverse bias operation of a non-irradiated detector rather “normal” $T < 15\text{K}$